PCN Number: 2			20180423002					PCN Date:			ite:	May 9, 2018		
- ,			mbly Material set for Selected Device(s)											
Custo	omer Contact:	PCN I	<u>Manager</u>		Dept	: Q	uality Se							
Proposed 1 st Ship Date:			Aug. 9, 2018				Estimated Sample Availability:			Date provided sample reque				
Chan	ige Type:													
	Assembly Site				Design					١	Wafer Bu	mp Site		
	Assembly Process		Data Sheet					☐ Wafer Bump Material						
	Assembly Materials		Part numl									Vafer Bump Process		
	Mechanical Specific		n Test Site							_		er Fab Site		
F	Packing/Shipping/L	_abel	ling Test Process			5		Щ	_	Wafer Fab Materials				
										1	Wafer Fal	Fab Process		
					PCN	Det	ails							
Desc	ription of Change	e:												
Texas Instruments is pleased to announce the qualification of new assembly material set for devices listed in "Product affected" section below. Devices will remain in current assembly facility and piece part changes as follows:														
	Material		<u> </u>		urrent			Proposed						
	Mount Compound				42062	201		4208458						
	Mold Compound		<u> </u>		205443			4211649						
Lead finish			Standard NiPdAu				Roughened NiPdAu (Single side)							
	on for Change:													
Continuity of supply.														
Antic	Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):													
None														
Antic	cipated impact or	n Ma	terial	Dec	laration									
Material Declaration				production data and will be available following the production										
				release. Upon production release the revised reports can be										
				obtained from the <u>TI Eco-Info website</u> . There is no impact to the										
			material meeting current regulatory compliance requirements											
			with this PCN change.											
Chan	Changes to product identification resulting from this PCN:													
None.														
Prod	uct Affected:													
DRV401AIDWP OPA			Δ569ΔII	אַר	DG4	THS	THS6012CDWPR				TDΔ61	20A2DWP		
		1	PA569AIDWPG4 PA569AIDWPR				THS6012CDWPR					20A2DWPG4		
										+				
		1	N0301043DWP N0301043DWPR			THS6012IDWPR					20A2DWPR	+		
			HS6002CDWP			THS6032CDWP THS6032IDWP					TPA6120A2DWPRG4 TPPM0110DWP			
			HS6002CDWPG4			THS6032IDWPR							\dashv	
												110DWPR	\dashv	
			<u> 1S6002IDWP</u> 1S6002IDWPR				TPA1517DWP TPPM0111DWP TPA1517DWPG4				TITONAL	+		
			HS6012CDWP				PA1517DWPG4 PA1517DWPR					-		
												+		
OPA569AIDWP TH			HS6012CDWPG4			IIFA	TPA1517DWPRG4				1		1	

Qualification Report

HSOIC G700LB + FS849 Enterprise Qualification in TITL

Approve Date 11-Apr-2018

Product Attributes

Attributes	Qual Device: <u>DRV401AIDWPR</u>	QBS Package Reference: TPS653853QDCARQ1
Assembly Site	TAI	TAI
Package Family	HSOIC	HTSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DMO5S	RFAB/DMOS6 (MFF)
Wafer Fab Process	50HPA07	LBC8

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

	_ = = = = = = = = = = = = = = = = = = =	3. Number of lots / Total sam			
Туре	Test Name / Condition	Duration	Qual Device: DRV401AIDWPR	QBS Package Reference: <u>TPS653853QDCARQ1</u>	
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	
CDM	ESD - CDM - Q100	1000 V corner pins only	-	1/3/0	
CDM	ESD - CDM - Q100	750 V (all pins)	-	1/3/0	
ED	Auto Electrical Distributions	Cpk>1.67 Room, hot, and cold test	-	1/90/0	
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0	
ELFR	Early Life Failure Rate, 150C	48 Hours	-	1/805/0	
HAST	Biased HAST, 130C/85%RH	192 Hours (for information)	-	3/231/0	
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	
HBM	ESD - HBM - Q100	2000 V	-	1/3/0	
HTOL	Life Test, 125C	1000 Hours	-	3/231/0	
HTSL	High Temp Storage Bake 150C	1000 Hours	-	3/231/0	
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-	
LI	Lead Integrity	Leads	3/135/0	-	
LI	Lead Pull	Leads	3/135/0	-	
LU	Latch-up	(per JESD78)	-	1/6/0	
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	-	
MQ	Manufacturability (Auto Assembly)	(per automotive requirements)	-	Pass	
PD	Physical Dimension	-	3/90/0	-	
PTC	Power Temperature Cycle, - 40/125C	1000 cycles	-	1/47/0	
SD	Surface Mount Solderability	>95% Lead Coverage	3/66/0	-	
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0	
TC	Temperature Cycle, -65/150C	1000 Cycles	-	3/231/0	
WBP	Post Temp. Cycle Bond Pull	500 Cycles	-	3/15/0	
WBP	Bond Pull	Wires	3/228/0	-	
WBS Ball Bond Shear		Wires	3/228/0	-	

⁻ Qual Device DRV401AIDWPR is qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

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